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ELECTRICAL TEST PROBE

Thomas F. Bauman, Westlake, OH Inventor:

(US)

Hickok, Incorporated, Cleveland, OH (73)

(US)

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(51)

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(58)324/149, 156, 508, 509, 538; 340/815.74

(56)**References Cited**

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Primary Examiner—Antoine Duval Davis (74) Attorney, Agent, or Firm—Donald A. Bergquist

CLAIM (57)

The ornamental design for an electrical test probe, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of the electrical test probe of this invention showing a detachable primary probe point detached to reveal a non-detachable secondary sharp probe point;

FIG. 2 is a top view thereof with the secondary probe point covered;

FIG. 3 is a top view thereof to clearly illustrate the location of views shown in FIGS. 8, 9 and 10;

FIG. 4 is a front view thereof with the secondary probe point covered, the back view being a mirror image of the front view;

FIG. 5 is a bottom view thereof with the secondary probe point covered;

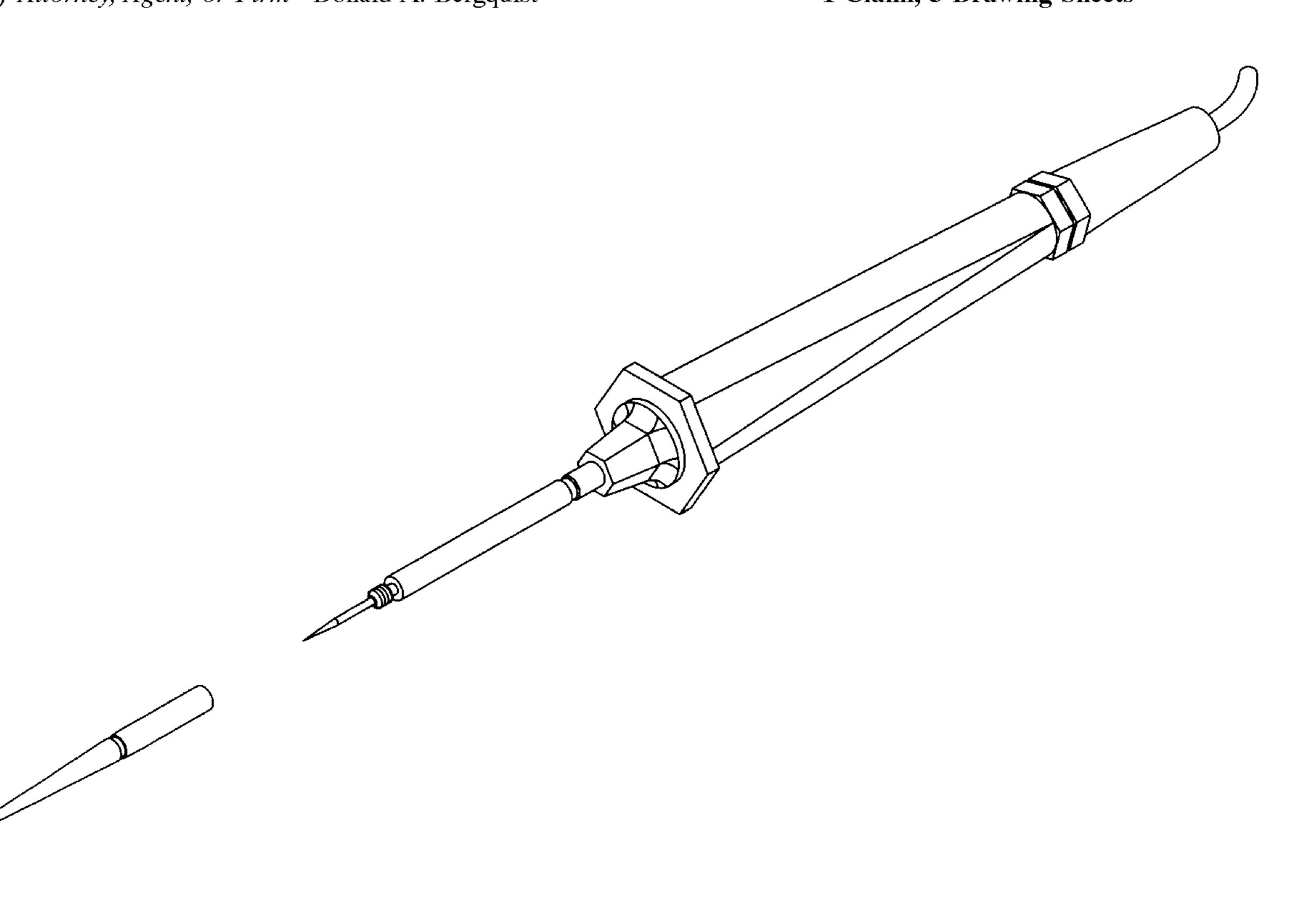
FIG. 6 is a left side view thereof;

FIG. 7 is a right side view thereof;

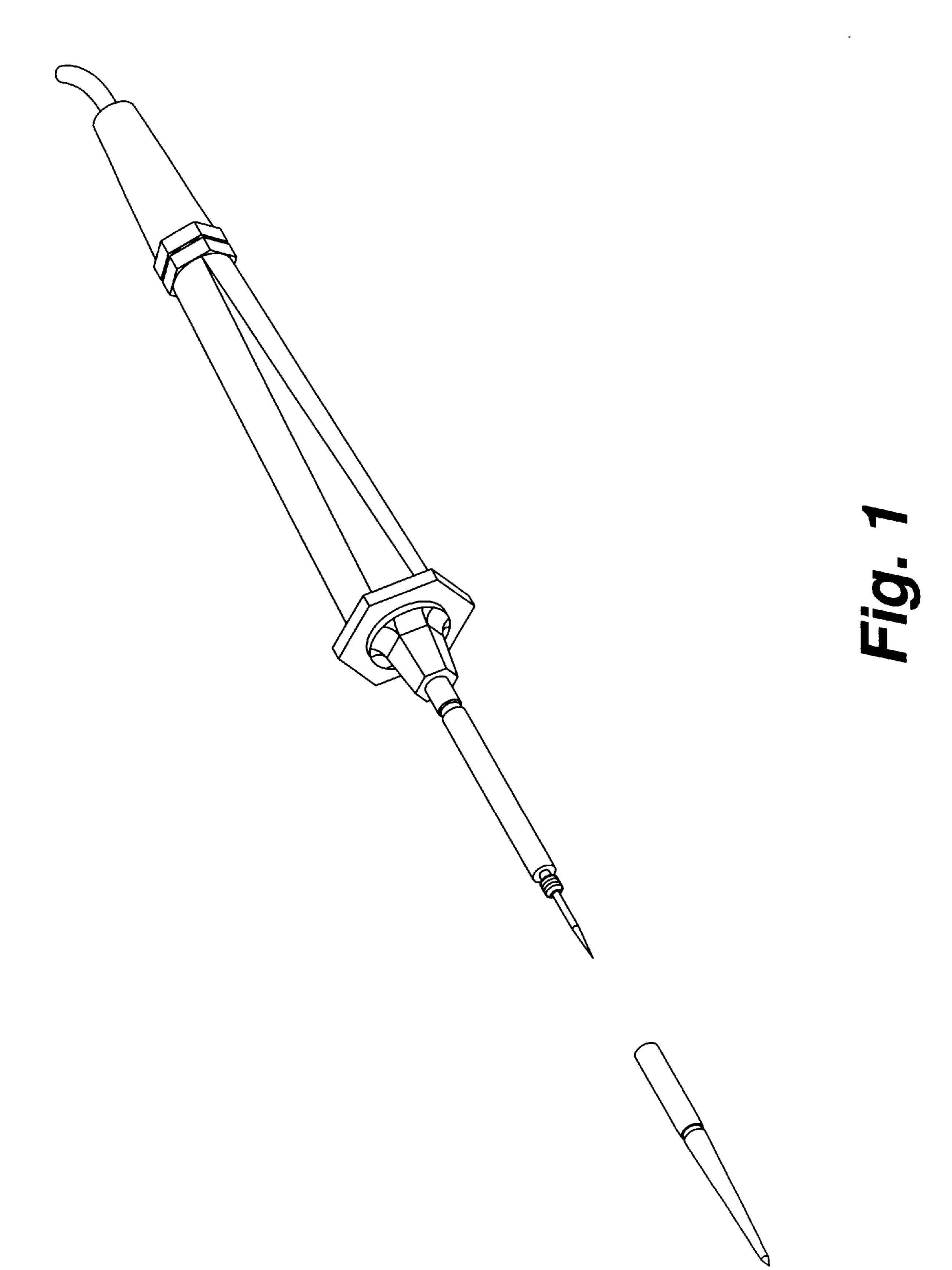
FIG. 8 is a view of the exterior surfaces only of what would be seen were the probe cut and viewed along the line 8—8; FIG. 9 is a view of the exterior surfaces only of what would be seen were the probe cut and viewed along the line 9—9; and,

FIG. 10 is a view of the exterior surfaces only of what would be seen were the probe cut and viewed along the line **10—10**.

1 Claim, 3 Drawing Sheets



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